## Notice of References Cited Application/Control No. | Applicant(s)/Patent Under Reexamination | TAN ET AL. | Examiner | Art Unit | Page 1 of 1

## **U.S. PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	А	US-6,665,455	12-2003	Ting, Chih-Yu	382/312
*	В	US-6,977,187	12-2005	Farrell et al.	438/106
*	С	US-7,084,922	08-2006	Miyake, Hiroyuki	348/373
*	D	US-2005/0007485	01-2005	Vook et al.	348/345
*	F	US-2005/0007484	01-2005	Tan et al.	348/340
*	F	US-6,741,286	05-2004	Meek et al.	348/370
*	G	US-2005/0052568	03-2005	Tan et al.	348/374
*	Н	US-6,392,688	05-2002	Barman et al.	348/42
	-	US-			
	J	US-			
	К	US-			
	L	US-			
	М	US-			•

## FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	2					
	0					
	Р		( - )			
	Q				1172	
	R					
	S					
	T.	•			·	

## **NON-PATENT DOCUMENTS**

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
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	w	
	x	

\*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).) Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.